Docket No.

217075US2PCT





1765

0 6 MAY 2003

# IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

IN RE APPLICATION OF:

Joseph T. VERDEYEN, et al.

SERIAL NO:

10/031,570

GAU:

FILED:

FOR:

**EXAMINER:** January 22, 2002 ELECTRON DENSITY MEASUREMENT AND PLASMA PROCESS CONTROL SYSTEM USING

IN THE RESONANT FREQUENCY OF AN OPEN RESONATOR CONTAINING THE PLASMA

INFORMATION DISCLOSURE STATEMENT UNDER 37 CFR 1.9

COMMISSIONER FOR PATENTS ALEXANDRIA, VIRGINIA 22313

Applicant(s) wish to disclose the following information.

## REFERENCES

- The applicant(s) wish to make of record the references listed on the attached form PTO-1449. Copies of the listed references are attached, where required, as are either statements of relevancy or any readily available English translations of pertinent portions of any non-English language references.
- ☐ A check is attached in the amount required under 37 CFR §1.17(p).

### RELATED CASES

- Attached is a list of applicant's pending application(s) or issued patent(s) which may be related to the present application. A copy of the patent(s), together with a copy of the claims and drawings of the pending application(s) is attached along with PTO 1449.
- A check is attached in the amount required under 37 CFR §1.17(p).

# CERTIFICATION

- ☐ Each item of information contained in this information disclosure statement was first cited in a communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this statement.
- □ No item of information contained in this information disclosure statement was cited in a communication from a foreign patent office in a counterpart foreign application or, to the knowledge of the undersigned, having made reasonable inquiry, was known to any individual designated in 37 CFR §1.56(c) more than three months prior to the filing of this statement.

## DEPOSIT ACCOUNT

Please charge any additional fees for the papers being filed herewith and for which no check is enclosed herewith, or credit any overpayment to deposit account number 15-0030. A duplicate copy of this sheet is enclosed.

Respectfully submitted,

OBLON, SPIVAK, McCLELLAND, MAIER & 1

Michael R. Casey

Registration No. 40,294

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Tel. (703) 413-3000 Fax. (703) 413-2220 (OSMMN 05/03)

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	AA	2,405,229	8-6-1946	MUELLER et al.					
· ·	AB	2,483,189	9-27-1949	C. C. EAGLESFIELD					
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	AP	WO 01/06544	1-25-2001	WIPO		•			
	AQ	WO 01/37306	5-25-2001	WIPO					
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\*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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